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Applications of **Embedded - Microprocessors**

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

Product Status	Obsolete
Core Processor	MPC8xx
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	50MHz
Co-Processors/DSP	Communications; CPM
RAM Controllers	DRAM
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10Mbps (4), 10/100Mbps (1)
SATA	-
USB	-
Voltage - I/O	3.3V
Operating Temperature	-40°C ~ 95°C (TA)
Security Features	-
Package / Case	357-BBGA
Supplier Device Package	357-PBGA (25x25)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/kmpc860tczq50d4

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Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



2 Features

The following list summarizes the key MPC860 features:

- Embedded single-issue, 32-bit core (implementing the Power Architecture technology) with thirty-two 32-bit general-purpose registers (GPRs)
 - The core performs branch prediction with conditional prefetch without conditional execution.
 - 4- or 8-Kbyte data cache and 4- or 16-Kbyte instruction cache (see Table 1)
 - 16-Kbyte instruction caches are four-way, set-associative with 256 sets; 4-Kbyte instruction caches are two-way, set-associative with 128 sets.
 - 8-Kbyte data caches are two-way, set-associative with 256 sets; 4-Kbyte data caches are two-way, set-associative with 128 sets.
 - Cache coherency for both instruction and data caches is maintained on 128-bit (4-word) cache blocks.
 - Caches are physically addressed, implement a least recently used (LRU) replacement algorithm, and are lockable on a cache block basis.
 - MMUs with 32-entry TLB, fully-associative instruction, and data TLBs
 - MMUs support multiple page sizes of 4-, 16-, and 512-Kbytes, and 8-Mbytes; 16 virtual address spaces and 16 protection groups
 - Advanced on-chip-emulation debug mode
- Up to 32-bit data bus (dynamic bus sizing for 8, 16, and 32 bits)
- 32 address lines
- Operates at up to 80 MHz
- Memory controller (eight banks)
 - Contains complete dynamic RAM (DRAM) controller
 - Each bank can be a chip select or \overline{RAS} to support a DRAM bank.
 - Up to 15 wait states programmable per memory bank
 - Glueless interface to DRAM, SIMMS, SRAM, EPROM, Flash EPROM, and other memory devices
 - DRAM controller programmable to support most size and speed memory interfaces
 - Four $\overline{\text{CAS}}$ lines, four $\overline{\text{WE}}$ lines, and one $\overline{\text{OE}}$ line
 - Boot chip-select available at reset (options for 8-, 16-, or 32-bit memory)
 - Variable block sizes (32 Kbytes to 256 Mbytes)
 - Selectable write protection
 - On-chip bus arbitration logic
- General-purpose timers
 - Four 16-bit timers or two 32-bit timers
 - Gate mode can enable/disable counting
 - Interrupt can be masked on reference match and event capture.



Thermal Calculation and Measurement

7 Thermal Calculation and Measurement

For the following discussions, $P_D = (V_{DD} \times I_{DD}) + PI/O$, where PI/O is the power dissipation of the I/O drivers.

7.1 Estimation with Junction-to-Ambient Thermal Resistance

An estimation of the chip junction temperature, T_J, in °C can be obtained from the equation:

$$T_J = T_A + (R_{\theta JA} \times P_D)$$

where:

 T_A = ambient temperature (°C)

 $R_{\theta JA}$ = package junction-to-ambient thermal resistance (°C/W)

 P_D = power dissipation in package

The junction-to-ambient thermal resistance is an industry standard value which provides a quick and easy estimation of thermal performance. However, the answer is only an estimate; test cases have demonstrated that errors of a factor of two (in the quantity $T_J - T_A$) are possible.

7.2 Estimation with Junction-to-Case Thermal Resistance

Historically, the thermal resistance has frequently been expressed as the sum of a junction-to-case thermal resistance and a case-to-ambient thermal resistance:

 $R_{\theta JA} = R_{\theta JC} + R_{\theta CA}$

where:

 $R_{\theta JA}$ = junction-to-ambient thermal resistance (°C/W)

 $R_{\theta IC}$ = junction-to-case thermal resistance (°C/W)

 $R_{\theta CA}$ = case-to-ambient thermal resistance (°C/W)

 $R_{\theta JC}$ is device related and cannot be influenced by the user. The user adjusts the thermal environment to affect the case-to-ambient thermal resistance, $R_{\theta CA}$. For instance, the user can change the airflow around the device, add a heat sink, change the mounting arrangement on the printed-circuit board, or change the thermal dissipation on the printed-circuit board surrounding the device. This thermal model is most useful for ceramic packages with heat sinks where some 90% of the heat flows through the case and the heat sink to the ambient environment. For most packages, a better model is required.

7.3 Estimation with Junction-to-Board Thermal Resistance

A simple package thermal model which has demonstrated reasonable accuracy (about 20%) is a two-resistor model consisting of a junction-to-board and a junction-to-case thermal resistance. The junction-to-case thermal resistance covers the situation where a heat sink is used or where a substantial amount of heat is dissipated from the top of the package. The junction-to-board thermal resistance describes the thermal performance when most of the heat is conducted to the printed-circuit board. It has been observed that the thermal performance of most plastic packages, especially PBGA packages, is strongly dependent on the board temperature; see Figure 2.



Thermal Calculation and Measurement



Figure 2. Effect of Board Temperature Rise on Thermal Behavior

If the board temperature is known, an estimate of the junction temperature in the environment can be made using the following equation:

$$T_{J} = T_{B} + (R_{\theta JB} \times P_{D})$$

where:

 $R_{\theta JB}$ = junction-to-board thermal resistance (°C/W)

 $T_B = board temperature (°C)$

 P_D = power dissipation in package

If the board temperature is known and the heat loss from the package case to the air can be ignored, acceptable predictions of junction temperature can be made. For this method to work, the board and board mounting must be similar to the test board used to determine the junction-to-board thermal resistance, namely a 2s2p (board with a power and a ground plane) and by attaching the thermal balls to the ground plane.

7.4 Estimation Using Simulation

When the board temperature is not known, a thermal simulation of the application is needed. The simple two-resistor model can be used with the thermal simulation of the application [2], or a more accurate and complex model of the package can be used in the thermal simulation.

7.5 Experimental Determination

To determine the junction temperature of the device in the application after prototypes are available, the thermal characterization parameter (Ψ_{JT}) can be used to determine the junction temperature with a measurement of the temperature at the top center of the package case using the following equation:

$$T_J = T_T + (\Psi_{JT} \times P_D)$$



Layout Practices

where:

 Ψ_{JT} = thermal characterization parameter

 T_T = thermocouple temperature on top of package

 P_D = power dissipation in package

The thermal characterization parameter is measured per JEDEC JESD51-2 specification using a 40 gauge type T thermocouple epoxied to the top center of the package case. The thermocouple should be positioned so that the thermocouple junction rests on the package. A small amount of epoxy is placed over the thermocouple junction and over 1 mm of wire extending from the junction. The thermocouple wire is placed flat against the package case to avoid measurement errors caused by cooling effects of the thermocouple wire.

7.6 References

Semiconductor Equipment and Materials International	(415) 964-5111
805 East Middlefield Rd.	
Mountain View, CA 94043	
MIL-SPEC and EIA/JESD (JEDEC) Specifications	800-854-7179 or
(Available from Global Engineering Documents)	303-397-7956
JEDEC Specifications	http://www.jedec.org

- 1. C.E. Triplett and B. Joiner, "An Experimental Characterization of a 272 PBGA Within an Automotive Engine Controller Module," Proceedings of SemiTherm, San Diego, 1998, pp. 47–54.
- B. Joiner and V. Adams, "Measurement and Simulation of Junction to Board Thermal Resistance and Its Application in Thermal Modeling," Proceedings of SemiTherm, San Diego, 1999, pp. 212–220.

8 Layout Practices

Each V_{DD} pin on the MPC860 should be provided with a low-impedance path to the board's supply. Each GND pin should likewise be provided with a low-impedance path to ground. The power supply pins drive distinct groups of logic on the chip. The V_{DD} power supply should be bypassed to ground using at least four 0.1 µF-bypass capacitors located as close as possible to the four sides of the package. The capacitor leads and associated printed circuit traces connecting to chip V_{DD} and GND should be kept to less than half an inch per capacitor lead. A four-layer board employing two inner layers as V_{CC} and GND planes is recommended.

All output pins on the MPC860 have fast rise and fall times. Printed circuit (PC) trace interconnection length should be minimized in order to minimize undershoot and reflections caused by these fast output switching times. This recommendation particularly applies to the address and data buses. Maximum PC trace lengths of 6 inches are recommended. Capacitance calculations should consider all device loads as well as parasitic capacitances due to the PC traces. Attention to proper PCB layout and bypassing becomes especially critical in systems with higher capacitive loads because these loads create higher transient currents in the V_{CC} and GND circuits. Pull up all unused inputs or signals that will be inputs during reset. Special care should be taken to minimize the noise levels on the PLL supply pins.





9 Bus Signal Timing

Table 7 provides the bus operation timing for the MPC860 at 33, 40, 50, and 66 MHz.

The maximum bus speed supported by the MPC860 is 66 MHz. Higher-speed parts must be operated in half-speed bus mode (for example, an MPC860 used at 80 MHz must be configured for a 40-MHz bus).

The timing for the MPC860 bus shown assumes a 50-pF load for maximum delays and a 0-pF load for minimum delays.

NI	Oheresteristis	33 MHz		40 MHz		50 MHz		66 MHz		11 14
NUM	Characteristic	Min	Max	Min	Max	Min	Max	Min	Max	Unit
B1	CLKOUT period	30.30	30.30	25.00	30.30	20.00	30.30	15.15	30.30	ns
B1a	EXTCLK to CLKOUT phase skew (EXTCLK > 15 MHz and MF <= 2)	-0.90	0.90	-0.90	0.90	-0.90	0.90	-0.90	0.90	ns
B1b	EXTCLK to CLKOUT phase skew (EXTCLK > 10 MHz and MF < 10)	-2.30	2.30	-2.30	2.30	-2.30	2.30	-2.30	2.30	ns
B1c	CLKOUT phase jitter (EXTCLK > 15 MHz and MF <= 2) ¹	-0.60	0.60	-0.60	0.60	-0.60	0.60	-0.60	0.60	ns
B1d	CLKOUT phase jitter ¹	-2.00	2.00	-2.00	2.00	-2.00	2.00	-2.00	2.00	ns
B1e	CLKOUT frequency jitter (MF < 10) ¹	_	0.50	_	0.50	_	0.50	_	0.50	%
B1f	CLKOUT frequency jitter (10 < MF < 500) ¹	_	2.00	_	2.00	_	2.00	_	2.00	%
B1g	CLKOUT frequency jitter (MF > 500) ¹	_	3.00	—	3.00	_	3.00	_	3.00	%
B1h	Frequency jitter on EXTCLK ²	_	0.50	_	0.50	_	0.50	_	0.50	%
B2	CLKOUT pulse width low	12.12	—	10.00	_	8.00	—	6.06	_	ns
B3	CLKOUT width high	12.12	—	10.00	_	8.00	—	6.06	_	ns
B4	CLKOUT rise time ³	_	4.00	—	4.00	—	4.00	—	4.00	ns
B5 ³³	CLKOUT fall time ³	_	4.00	—	4.00	—	4.00	—	4.00	ns
B7	CLKOUT to A(0:31), BADDR(28:30), RD/WR, BURST, D(0:31), DP(0:3) invalid	7.58	—	6.25	—	5.00	—	3.80	—	ns
B7a	CLKOUT to TSIZ(0:1), REG, RSV, AT(0:3), BDIP, PTR invalid	7.58	—	6.25	—	5.00	—	3.80	—	ns
B7b	CLKOUT to BR, BG, FRZ, VFLS(0:1), VF(0:2) IWP(0:2), LWP(0:1), STS invalid ⁴	7.58	—	6.25	—	5.00	—	3.80	—	ns
B8	CLKOUT to A(0:31), BADDR(28:30) RD/WR, BURST, D(0:31), DP(0:3) valid	7.58	14.33	6.25	13.00	5.00	11.75	3.80	10.04	ns
B8a	CLKOUT to TSIZ(0:1), REG, RSV, AT(0:3) BDIP, PTR valid	7.58	14.33	6.25	13.00	5.00	11.75	3.80	10.04	ns
B8b	CLKOUT to BR, BG, VFLS(0:1), VF(0:2), IWP(0:2), FRZ, LWP(0:1), STS valid ⁴	7.58	14.33	6.25	13.00	5.00	11.75	3.80	10.04	ns

Table 7. Bus Operation Timings



		33 MHz		40 MHz		50 MHz		66 MHz		
Num			Мах	Min	Max	Min	Мах	Min	Max	Unit
B23	CLKOUT rising edge to \overline{CS} negated GPCM read access, GPCM write access ACS = 00, TRLX = 0, and CSNT = 0	2.00	8.00	2.00	8.00	2.00	8.00	2.00	8.00	ns
B24	A(0:31) and BADDR(28:30) to \overline{CS} asserted GPCM ACS = 10, TRLX = 0	5.58	—	4.25	_	3.00	_	1.79	—	ns
B24a	A(0:31) and BADDR(28:30) to \overline{CS} asserted GPCM ACS = 11, TRLX = 0	13.15	—	10.50	—	8.00	—	5.58	—	ns
B25	CLKOUT rising edge to \overline{OE} , \overline{WE} (0:3) asserted	—	9.00	—	9.00	—	9.00	—	9.00	ns
B26	CLKOUT rising edge to OE negated	2.00	9.00	2.00	9.00	2.00	9.00	2.00	9.00	ns
B27	A(0:31) and BADDR(28:30) to \overline{CS} asserted GPCM ACS = 10, TRLX = 1	35.88	_	29.25	_	23.00	_	16.94	_	ns
B27a	A(0:31) and BADDR(28:30) to \overline{CS} asserted GPCM ACS = 11, TRLX = 1	43.45	—	35.50	—	28.00	—	20.73	—	ns
B28	CLKOUT rising edge to $\overline{WE}(0:3)$ negated GPCM write access CSNT = 0	—	9.00	—	9.00	—	9.00	—	9.00	ns
B28a	CLKOUT falling edge to $\overline{WE}(0:3)$ negated GPCM write access TRLX = 0, 1, CSNT = 1, EBDF = 0	7.58	14.33	6.25	13.00	5.00	11.75	3.80	10.54	ns
B28b	CLKOUT falling edge to \overline{CS} negated GPCM write access TRLX = 0, 1, CSNT = 1, ACS = 10, or ACS = 11, EBDF = 0	—	14.33	—	13.00		11.75		10.54	ns
B28c	CLKOUT falling edge to \overline{WE} (0:3) negated GPCM write access TRLX = 0, 1, CSNT = 1 write access TRLX = 0, CSNT = 1, EBDF = 1	10.86	17.99	8.88	16.00	7.00	14.13	5.18	12.31	ns
B28d	CLKOUT falling edge to \overline{CS} negated GPCM write access TRLX = 0, 1, CSNT = 1, ACS = 10, or ACS = 11, EBDF = 1	_	17.99	_	16.00		14.13		12.31	ns
B29	$\overline{WE}(0:3)$ negated to D(0:31), DP(0:3) High-Z GPCM write access CSNT = 0, EBDF = 0	5.58	_	4.25	—	3.00	—	1.79	—	ns
B29a	$\overline{WE}(0:3)$ negated to D(0:31), DP(0:3) High-Z GPCM write access, TRLX = 0, CSNT = 1, EBDF = 0	13.15	—	10.5	—	8.00		5.58	—	ns
B29b	$\overline{\text{CS}}$ negated to D(0:31), DP(0:3), High-Z GPCM write access, ACS = 00, TRLX = 0, 1, and CSNT = 0	5.58		4.25		3.00		1.79		ns
B29c	$\overline{\text{CS}}$ negated to D(0:31), DP(0:3) High-Z GPCM write access, TRLX = 0, CSNT = 1, ACS = 10, or ACS = 11, EBDF = 0	13.15		10.5		8.00		5.58		ns

Table 7. Bus Operation Timings (continued)



		33 MHz		40 MHz		50 MHz		66 MHz		
Num	Characteristic	Min	Max	Min	Max	Min	Max	Min	Max	Unit
B31a	CLKOUT falling edge to CS valid—as requested by control bit CST1 in the corresponding word in UPM	7.58	14.33	6.25	13.00	5.00	11.75	3.80	10.54	ns
B31b	CLKOUT rising edge to \overline{CS} valid—as requested by control bit CST2 in the corresponding word in UPM	1.50	8.00	1.50	8.00	1.50	8.00	1.50	8.00	ns
B31c	CLKOUT rising edge to $\overline{\text{CS}}$ valid—as requested by control bit CST3 in the corresponding word in UPM	7.58	14.33	6.25	13.00	5.00	11.75	3.80	10.04	ns
B31d	CLKOUT falling edge to \overline{CS} valid—as requested by control bit CST1 in the corresponding word in UPM, EBDF = 1	13.26	17.99	11.28	16.00	9.40	14.13	7.58	12.31	ns
B32	CLKOUT falling edge to BS valid—as requested by control bit BST4 in the corresponding word in UPM	1.50	6.00	1.50	6.00	1.50	6.00	1.50	6.00	ns
B32a	CLKOUT falling edge to \overline{BS} valid—as requested by control bit BST1 in the corresponding word in UPM, EBDF = 0	7.58	14.33	6.25	13.00	5.00	11.75	3.80	10.54	ns
B32b	CLKOUT rising edge to $\overline{\text{BS}}$ valid—as requested by control bit BST2 in the corresponding word in UPM	1.50	8.00	1.50	8.00	1.50	8.00	1.50	8.00	ns
B32c	CLKOUT rising edge to $\overline{\text{BS}}$ valid—as requested by control bit BST3 in the corresponding word in UPM	7.58	14.33	6.25	13.00	5.00	11.75	3.80	10.54	ns
B32d	CLKOUT falling edge to \overline{BS} valid—as requested by control bit BST1 in the corresponding word in UPM, EBDF = 1	13.26	17.99	11.28	16.00	9.40	14.13	7.58	12.31	ns
B33	CLKOUT falling edge to GPL valid—as requested by control bit GxT4 in the corresponding word in UPM	1.50	6.00	1.50	6.00	1.50	6.00	1.50	6.00	ns
B33a	CLKOUT rising edge to GPL valid—as requested by control bit GxT3 in the corresponding word in UPM	7.58	14.33	6.25	13.00	5.00	11.75	3.80	10.54	ns
B34	A(0:31), BADDR(28:30), and D(0:31) to \overline{CS} valid—as requested by control bit CST4 in the corresponding word in UPM	5.58	—	4.25	—	3.00	—	1.79	—	ns
B34a	A(0:31), BADDR(28:30), and D(0:31) to \overline{CS} valid—as requested by control bit CST1 in the corresponding word in UPM	13.15		10.50		8.00		5.58	_	ns
B34b	A(0:31), BADDR(28:30), and D(0:31) to \overline{CS} valid—as requested by control bit CST2 in the corresponding word in UPM	20.73	_	16.75		13.00		9.36	_	ns

Table 7. Bus Operation Timings (continued)









Figure 12. External Bus Read Timing (GPCM Controlled—TRLX = 0, ACS = 11)



Bus Signal Timing



Figure 20 provides the timing for the synchronous external master access controlled by the GPCM.

Figure 20. Synchronous External Master Access Timing (GPCM Handled ACS = 00)

Figure 21 provides the timing for the asynchronous external master memory access controlled by the GPCM.





Figure 22 provides the timing for the asynchronous external master control signals negation.



Figure 22. Asynchronous External Master—Control Signals Negation Timing



IEEE 1149.1 Electrical Specifications



Figure 35. JTAG Test Clock Input Timing



Figure 36. JTAG Test Access Port Timing Diagram



Figure 37. JTAG TRST Timing Diagram





11 CPM Electrical Characteristics

This section provides the AC and DC electrical specifications for the communications processor module (CPM) of the MPC860.

11.1 PIP/PIO AC Electrical Specifications

Table 14 provides the PIP/PIO AC timings as shown in Figure 39 through Figure 43.

Table 14. PIP/PIO Timing

Num	Characteristic	All Freq	Unit	
Num	Onardetensite	Min	Max	Onit
21	Data-in setup time to STBI low	0	_	ns
22	Data-in hold time to STBI high	2.5 – t3 ¹	_	CLK
23	STBI pulse width	1.5	_	CLK
24	STBO pulse width	1 CLK – 5 ns	_	ns
25	Data-out setup time to STBO low	2	_	CLK
26	Data-out hold time from STBO high	5	_	CLK
27	STBI low to STBO low (Rx interlock)	_	2	CLK
28	STBI low to STBO high (Tx interlock)	2	_	CLK
29	Data-in setup time to clock high	15	_	ns
30	Data-in hold time from clock high	7.5	_	ns
31	Clock low to data-out valid (CPU writes data, control, or direction)		25	ns

¹ t3 = Specification 23.



Figure 39. PIP Rx (Interlock Mode) Timing Diagram





Figure 42. PIP TX (Pulse Mode) Timing Diagram



Num	Charactariatia	All Freq	Unit	
	Characteristic	Min	Мах	Unit
42	SDACK assertion delay from clock high	—	12	ns
43	SDACK negation delay from clock low	—	12	ns
44	SDACK negation delay from TA low	—	20	ns
45	SDACK negation delay from clock high	_	15	ns
46	\overline{TA} assertion to rising edge of the clock setup time (applies to external \overline{TA})	7		ns

Table 16. IDMA Controller Timing (continued)



Figure 45. IDMA External Requests Timing Diagram



Figure 46. SDACK Timing Diagram—Peripheral Write, Externally-Generated TA



Num	Characteristic	All Freq	Unit	
	Characteristic	Min	Мах	Unit
84	L1CLK edge to L1CLKO valid (DSC = 1)	—	30.00	ns
85	L1RQ valid before falling edge of L1TSYNC ⁴	1.00	—	L1TCL K
86	L1GR setup time ²	42.00	—	ns
87	L1GR hold time	42.00	—	ns
88	L1CLK edge to L1SYNC valid (FSD = 00) CNT = 0000, BYT = 0, DSC = 0)	—	0.00	ns

Table 19. SI Timing (continued)

¹ The ratio SYNCCLK/L1RCLK must be greater than 2.5/1.

² These specs are valid for IDL mode only.

³ Where P = 1/CLKOUT. Thus, for a 25-MHz CLKO1 rate, P = 40 ns.

⁴ These strobes and TxD on the first bit of the frame become valid after L1CLK edge or L1SYNC, whichever comes later.



Figure 51. SI Receive Timing Diagram with Normal Clocking (DSC = 0)



CPM Electrical Characteristics







MPC860 PowerQUICC Family Hardware Specifications, Rev. 10







Figure 58. HDLC Bus Timing Diagram

11.8 Ethernet Electrical Specifications

Table 22 provides the Ethernet timings as shown in Figure 59 through Figure 63.

		All Freq	uencies	
Num	Characteristic	Min	Мах	Unit
120	CLSN width high	40		ns
121	RCLK1 rise/fall time	—	15	ns
122	RCLK1 width low	40	—	ns
123	RCLK1 clock period ¹	80	120	ns
124	RXD1 setup time	20	—	ns
125	RXD1 hold time	5	—	ns
126	RENA active delay (from RCLK1 rising edge of the last data bit)	10	—	ns
127	RENA width low	100	—	ns
128	TCLK1 rise/fall time	—	15	ns
129	TCLK1 width low	40	—	ns
130	TCLK1 clock period ¹	99	101	ns
131	TXD1 active delay (from TCLK1 rising edge)	10	50	ns
132	TXD1 inactive delay (from TCLK1 rising edge)	10	50	ns
133	TENA active delay (from TCLK1 rising edge)	10	50	ns
134	TENA inactive delay (from TCLK1 rising edge)	10	50	ns



CPM Electrical Characteristics





13.2 MII Transmit Signal Timing (MII_TXD[3:0], MII_TX_EN, MII_TX_ER, MII_TX_CLK)

The transmitter functions correctly up to a MII_TX_CLK maximum frequency of 25 MHz +1%. There is no minimum frequency requirement. In addition, the processor clock frequency must exceed the MII_TX_CLK frequency -1%.

Table 30 provides information on the MII transmit signal timing.

Table 30. MI	Transmit	Signal	Timing
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Num	Characteristic	Min	Max	Unit
M5	MII_TX_CLK to MII_TXD[3:0], MII_TX_EN, MII_TX_ER invalid	5	_	ns
M6	MII_TX_CLK to MII_TXD[3:0], MII_TX_EN, MII_TX_ER valid		25	
M7	MII_TX_CLK pulse width high	35	65%	MII_TX_CLK period
M8	MII_TX_CLK pulse width low	35%	65%	MII_TX_CLK period

Figure 73 shows the MII transmit signal timing diagram.



Figure 73. MII Transmit Signal Timing Diagram



Mechanical Data and Ordering Information

14.3 Mechanical Dimensions of the PBGA Package

Figure 77 shows the mechanical dimensions of the ZP PBGA package.



- 1. Dimensions and tolerance per ASME Y14.5M, 1994.
- 2. Dimensions in millimeters.
- 3. Dimension b is the maximum solder ball diameter measured parallel to data C.



22.40

E2

22.60